

33rd RD50 Workshop (CERN)

Tuesday 27 November 2018

Characterization Techniques - 6/2-024 - BE Auditorium Meyrin (15:50 - 17:00)

-Conveners: Gregor Kramberger

time	[id] title	presenter
15:50	[17] Novel view on extraction of charge carrier transport parameters from classical TCT	SHEPELEV, Artem
16:10	[24] Characterization of semiconductor detectors using IBIC imaging method	KARADZHINOVA-FERRER, Aneliya
16:30	[38] Discussion	KRAMBERGER, Gregor